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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/519,895	OKAYAMA ET AL.	MA ET AL.
Examiner	Art Unit	
Eric Wendler	2824	

SEARCHED						
Class	Subclass	Date	Examiner			
365	232	12/20/2005	EJW			
365	57	12/20/2005	EJW			
174	32	12/20/2005	EJW			
307	91	12/20/2005	EJW			
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
See attached EAST search history	12/20/2005	EJW			
Consulted examiners Rich Elms and John Hur for class recommendations	12/20/2005	EJW			
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